

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination
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	Examiner	Art Unit
	Maureen M. Wallenhorst	1743
		Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2005/0026301	02-2005	Petithory, Henry	436/180
	C	US-			
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	Oki et al. Japanese Journal of Applied Physics, vol. 42, pt. 1, no. 6A, June 2003, pages 3722-3727.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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